## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10575425	PROUET ET AL.
Examiner	Art Unit
JOHN W POOS	2816

SEARCHED					
Class	Subclass	Date	Examiner		
327	103	11/29/2007	JP		
323	315	12/3/2007	JP		

SEARCH NOTES				
Search Notes	Date	Examiner		
terms used to constrain subclasses above: chip, different sized transistors, transconductance, differential input voltage	11/29/2007	JP		
Inventor search in EAST and eDAN	12/3/2007	JP		
Update Search see attached Search History	4/25/2008	JP		

INTERFERENCE SEARCH					
Class	Subclass	Date	Examiner		

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